

# VTC 4000

### Near-field analysis of VCSEL arrays

#### Key features at a glance

- 2D measurement solution for near field characterization of VCSEL arrays
- Radiant power, polarization, position, divergence and peak wavelength for all single emitters
- Flat-field and absolute power calibration, traceable to national metrology standards
- ▲ Easy software integration by LumiSuite SDK

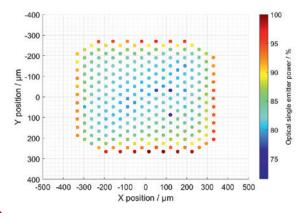


The VTC 4000 is Instrument System's VCSEL testing camera for comprehensive near-field analysis of complete VCSEL arrays. It enables the absolutely calibrated, traceable and polarization-controlled 2D characterization of all relevant parameters for every single emitter on the array. The VTC 4000, consisting of a camera and corresponding microscope optics, is capable of simultaneously determining position, radiant power and polarization of single emitters on a VCSEL array in a single-shot camera measurement. This allows quick and easy detection of defect emitters on the array. The integrated polarization analysis ensures an unprecedented radiant power measurement accuracy with minimal error budget.

## **\\** SINGLE EMITTER BEAM WAIST AND SPECTRAL ANALYSIS

By implementation of a z-translation stage, the camera enables the characterization of the single emitter beam profiles. In this way, the single emitters can be characterized in terms of beam waist, numerical aperture and M<sup>2</sup> value. For analysing the spectral parameters, the camera is optionally available in a version with fiber output. Connecting the VTC 4000 to a high-resolution CAS spectroradiometer enables measuring the peak wavelength of every single emitter.

The VTC 4000 can be easily integrated into handler systems with x-, y- and z- translation stages. This enables automated characterization of complete VCSEL arrays.



2D power measurement of single emitters on a VCSEL array.

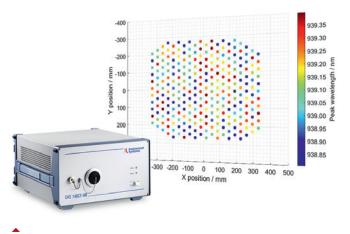
#### **MEASUREMENT RESULTS**

#### For each single emitter:

- Position (x and y)
- > Radiant flux
- > Polarization angle and degree
- >> Defect emitter analysis

#### With translation stages / optional features:

- Waist
- » Numerical aperture
- » M<sup>2</sup> value
- Focus position
- Peak wavelength



2D peak wavelength analysis of single emitters on a VCSEL array with the VTC 4000 version incl. fiber output. A high-resolution CAS spectroradiometer and an xy-translation stage is required.



#### **\\ TECHNICAL SPECIFICATIONS**

| VTC 4000   |   |
|--|---|
| General  |   |
| Dimensions (L x W x H)<br>(including objective lens, no handle)  | Version without fiber connector: 462 mm x 112.6 mm x 121 mm<br>Version with fiber connector: 462 mm x 185 mm x 121 mm |
| Weight   | Version without fiber connector: approx. 3.6 kg<br>Version with fiber connector: approx. 4.2 kg                       |
| Power Supply   | 24 V  |
| Operating temperature range  | 15 – 35 °C  |
| Interface  | Ethernet  |
| Trigger I/O  | Yes   |
| Camera system  |   |
| Camera sensor  | 12 Megapixel CMOS   |
| Camera spectral range  | 400 – 1000 nm   |
| OD Filter  | Standard OD9 (optimized for 650 – 1000 nm), others on request   |
| Calibration  | Possible in the range of 910 to 980 nm (e.g. 940 ±3 nm)   |
| Digital resolution   | 0.35 µm   |
| Optical resolution   | 2.2 µm (at 940 nm)  |
| Field of View  | 1.4 mm x 1.0 mm   |
| Integration times  | 100 µs – 1 s  |
| Typical acquisition time 2)  | ~700 ms   |
| Radiometric measurement accuracy 1)  | 6 %   |
| NA   | 0.26  |
| Wavelength measurement with CAS spectrometer <sup>3)</sup> (optional, for peak wavelength measurement) |   |
| Spectral range   | 800 nm – 1000 nm  |
| Spectral resolution (typical)  | 0.12 nm – 0.4 nm  |
| Data point interval (typical)  | 0.05 nm – 0.16 nm   |
| Filter wheel with optical density filters (typical)  | OD 0.5/1/1.5/2/2.5  |
| Measuring ranges (typical)   | 80 nm – 160 nm  |
| Wavelength accuracy  | ±0.05 nm  |
| Integration time   | 4 ms – 65 s   |
| Spatial resolution   | Diameter 20 µm  |

<sup>1)</sup> With factory calibration traceable to PTB.

<sup>2)</sup> Including data processing and transfer time per image

<sup>3)</sup> Exact specifications depend on the chosen high-resolution CAS model.

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